# **UT54ACTS04E**

Hex Inverters July, 2013 Datasheet www.aeroflex.com/Logic



#### **FEATURES**

- 0.6 µm CRH CMOS process
  - Latchup immune
- High speed
- Low power consumption
- Wide power supply operating range of 3.0V to 5.5V
- Available QML Q or V processes
- 14-pin flatpack
- UT54ACTS04E SMD 5962-96517

#### DESCRIPTION

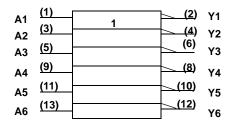
The UT54ACTS04E is a hex inveter. The circuit performs the Boolean functions  $Y = \overline{A} \cdot \overline{B}$  or  $Y = \overline{A} + \overline{B}$  in positive logic.

The device is characterized over full military temperature range of -55 $^{\circ}$ C to +125 $^{\circ}$ C.

#### **FUNCTION TABLE**

INPUT	OUTPUT
Α	Υ
Н	L
L	Н

#### LOGIC SYMBOL

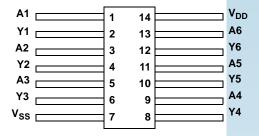


#### Note:

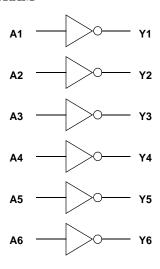
1. Logic symbol in accordance with ANSI/IEEE standard 91-1984 and IEC Publication 617-12.

#### **PINOUT**

#### 14-Lead Flatpack Top View



#### LOGIC DIAGRAM



#### OPERATIONAL ENVIRONMENT<sup>1</sup>

PARAMETER	LIMIT	UNITS
Total Dose	1.0E6	rads(Si)
SEU Threshold <sup>2</sup>	108	MeV-cm <sup>2</sup> /mg
SEL Threshold	120	MeV-cm <sup>2</sup> /mg
Neutron Fluence	1.0E14	n/cm <sup>2</sup>

#### **Notes:**

Logic will not latchup during radiation exposure within the limits defined in the table.
 Device storage elements are immune to SEU affects.

#### ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	LIMIT	UNITS
V <sub>DD</sub>	Supply voltage	-0.3 to 7.0	V
V <sub>I/O</sub>	Voltage any pin	3 to V <sub>DD</sub> +.3	V
T <sub>STG</sub>	Storage Temperature range	-65 to +150	°C
T <sub>J</sub>	Maximum junction temperature	+175	°C
T <sub>LS</sub>	Lead temperature (soldering 5 seconds) +300		°C
$\Theta_{ m JC}$	Thermal resistance junction to case 15.		°C/W
I <sub>I</sub>	DC input current ±10		mA
$P_D^2$	Maximum power dissipation permitted @ Tc=125°C	3.2	W

#### Note:

#### RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMIT	UNITS
V <sub>DD</sub>	Supply voltage	3.0 to 5.5	V
V <sub>IN</sub>	Input voltage any pin	0 to V <sub>DD</sub>	V
T <sub>C</sub>	Temperature range	-55 to + 125	°C

<sup>1.</sup>Stresses outside the listed absolute maximum ratings may cause permanent damage to the device. This is a stress rating only, functional operation of the device at these or any other conditions beyond limits indicated in the operational sections is not recommended. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

<sup>2.</sup> Per MIL-STD-883, method 1012.1, Section 3.4.1,  $P_D = (T_{j(max)}$  -  $T_{c(max)})$  /  $\Theta_{jc}$ 

## DC ELECTRICAL CHARACTERISTICS (Pre and Post-Radiation)\*

 $(V_{DD} = 3.3 \text{V to } 5.5 \text{V}; \ V_{SS} = \ 0 \text{V}^6, \ \text{-}55^{\circ}\text{C} < T_C < +125^{\circ}\text{C}); \ Unless otherwise noted, \ Tc is per the temperature range ordered and the contraction of the contractio$ 

SYMBOL	DESCRIPTION	CONDITION	MIN	MAX	UNIT
$V_{\rm IL1}$	Low-level input voltage <sup>1</sup>	V <sub>DD</sub> from 4.5V to 5.5V		0.8	V
$V_{\rm IL2}$	Low-level input voltage <sup>1</sup>	V <sub>DD</sub> from 3.0V to 3.6V		0.8	V
V <sub>IH1</sub>	High-level input voltage <sup>1</sup>	V <sub>DD</sub> from 4.5V to 5.5V	0.5 V <sub>DD</sub>		V
V <sub>IH2</sub>	High-level input voltage <sup>1</sup>	V <sub>DD</sub> from 3.0V to 3.6V	2.0		V
I <sub>IN</sub>	Input leakage current	$V_{IN} = V_{DD}$ or $V_{SS}$	-1	1	μΑ
V <sub>OL1</sub>	Low-level output voltage <sup>3</sup>	$I_{OL} = 8mA$ $V_{DD} = 4.5V \text{ to } 5.5V$		0.4	V
V <sub>OL2</sub>	Low-level output voltage <sup>3</sup>	$I_{OL} = 6mA$ $V_{DD} = 3.0V \text{ to } 3.6V$		0.4	V
V <sub>OH1</sub>	High-level output voltage <sup>3</sup>	$I_{OH} = -8mA$ $V_{DD}$ from 4.5V to 5.5V	0.7 V <sub>DD</sub>		V
V <sub>OH2</sub>	High-level output voltage <sup>3</sup>	$I_{OH} = -6mA$ $V_{DD}$ from 3.0V to 3.6V	2.4		V
I <sub>OS1</sub>	Short-circuit output current <sup>2</sup> , <sup>4</sup>	$V_{O} = V_{DD}$ and $V_{SS}$ $V_{DD}$ from 4.5V to 5.5V	-200	200	mA
$I_{OS2}$	Short-circuit output current <sup>2</sup> , <sup>4</sup>	$V_O = V_{DD}$ and $V_{SS}$ $V_{DD}$ from 3.0V to 3.6V	-100	100	mA
I <sub>OL1</sub>	Low level output current <sup>8</sup>	$V_{IN} = V_{DD}$ or $V_{SS}$ $V_{OL} = 0.4V$ $V_{DD}$ from 4.5V to 5.5V	8		mA
I <sub>OL2</sub>	Low level output current <sup>8</sup>	$V_{IN} = V_{DD}$ or $V_{SS}$ $V_{OL} = 0.4V$ $V_{DD}$ from 3.0V to 3.6V	6		mA
I <sub>OH1</sub>	High level output current <sup>8</sup>	$V_{IN} = V_{DD}$ or $V_{SS}$ $V_{OH} = V_{DD}$ -0.4V $V_{DD}$ from 4.5V to 5.5V	-8		mA
I <sub>OH2</sub>	High level output current <sup>8</sup>	$V_{IN} = V_{DD}$ or $V_{SS}$ $V_{OH} = V_{DD}$ -0.4V $V_{DD}$ from 3.0V to 3.6V	-6		mA
P <sub>total1</sub>	Power dissipation <sup>2, 7</sup>	$C_L = 50 pF$ $V_{DD} = 4.5 V$ to 5.5 V		1	mW/ MHz

P <sub>total2</sub>	Power dissipation <sup>2, 7</sup>	$C_L = 50 \text{pF}$ $V_{DD} = 3.0 \text{V to } 3.6 \text{V}$	0.5	mW/ MHz
I <sub>DDQ</sub>	Quiescent Supply Current	$V_{IN} = V_{DD}$ or $V_{SS}$	10	μА
		V <sub>DD</sub> from 3.6V to 5.5V		
$\Delta I_{\mathrm{DDQ}}$	Quiescent Supply Current Delta	For input under test	1.6	mA
		$V_{\rm IN} = V_{\rm DD} - 2.1V$		
		For all other inputs		
		$V_{IN} = V_{DD}$ or $V_{SS}$		
		$V_{\rm DD} = 5.5 V$		
C <sub>IN</sub>	Input capacitance <sup>5</sup>	f = 1 MHz	15	pF
		$V_{DD} = 0V$		
C <sub>OUT</sub>	Output capacitance <sup>5</sup>	f = 1 MHz	15	pF
		$V_{DD} = 0V$		

- \* For devices procured with a total ionizing dose tolerance guarantee, the post-irradiation performance is guaranteed at 25×C per MIL-STD-883 Method 1019, Condition A up to the maximum TID level procured.
- 1. Functional tests are conducted in accordance with MIL-STD-883 with the following input test conditions:  $V_{IH} = V_{IH}(min) + 20\%$ , 0%;  $V_{IL} = V_{IL}(max) + 0\%$ , 50%, as specified herein, for TTL, CMOS, or Schmitt compatible inputs. Devices may be tested using any input voltage within the above specified range, but are guaranteed to V<sub>IH</sub>(min) and V<sub>IL</sub>(max).
- 2. Supplied as a design limit but not guaranteed or tested.
- 3. Per MIL-PRF-38535, for current density ≤5.0E5 amps/cm², the maximum product of load capacitance (per output buffer) times frequency should not exceed 3,765pF/
- 4. Not more than one output may be shorted at a time for maximum duration of one second.

  5. Capacitance measured for initial qualification and when design changes may affect the value. Capacitance is measured between the designated terminal and V<sub>SS</sub> at frequency of 1MHz and a signal amplitude of 50mV rms maximum.
- 6. Maximum allowable relative shift equals 50mV.
- 7. Power dissipation specified per switching output.

  8. Parameter guaranteed by design and characterization, but is not tested.

#### AC ELECTRICAL CHARACTERISTICS (Pre and Post-Radiation)\*

 $(V_{DD} = 3.0 \text{V to } 5.5 \text{V}; V_{SS} = 0 \text{V}^{-1}, -55 \text{°C} < T_{C} < +125 \text{°C});$  Unless otherwise noted, Tc is per the temperature range ordered

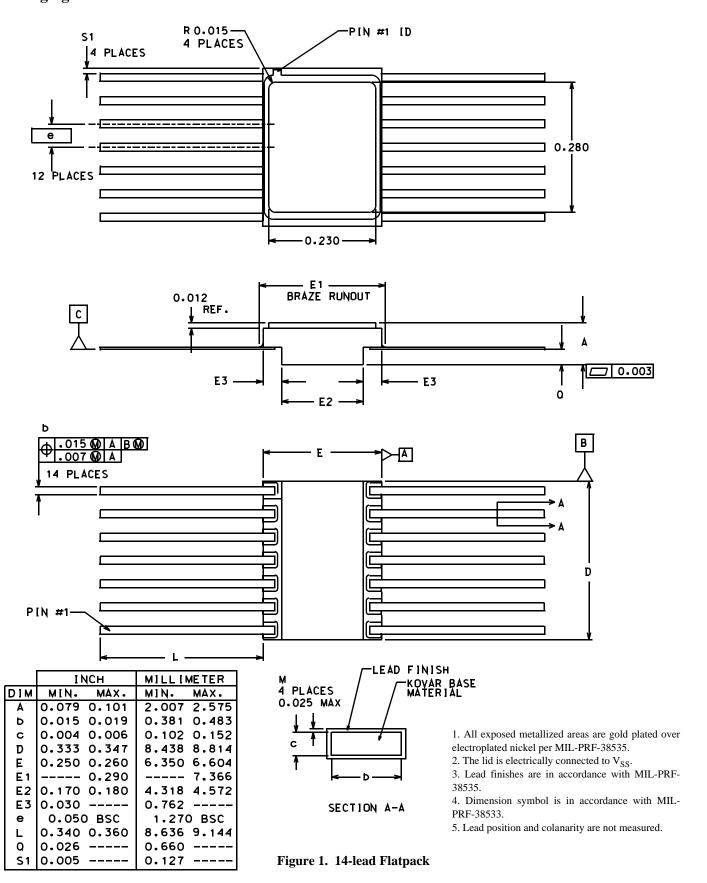
SYMBOL	PARAMETER	CONDITION	$V_{DD}$	MINIMUM	MAXIMUM	UNIT
t <sub>PLH</sub>	Input to Yn	$C_L = 50pF$	3.0V to 3.6V	2	14	ns
			4.5V to 5.5V	1	7	
t <sub>PHL</sub>	Input to Yn	$C_L = 50pF$	3.0V to 3.6V	2	14	ns
			4.5V to 5.5V	1	7	

#### Notes:

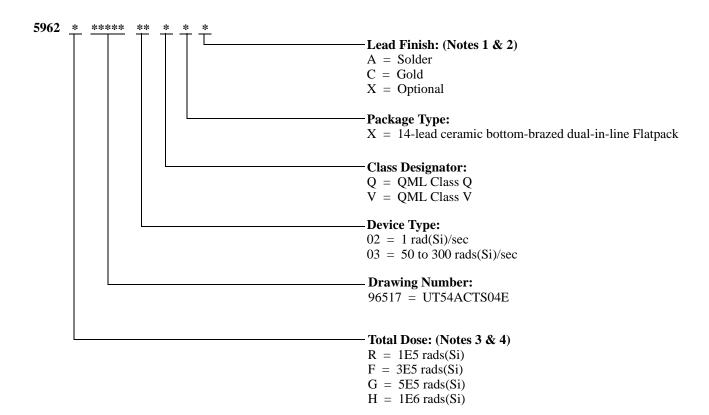
1. Maximum allowable relative shift equals 50mV.

<sup>\*</sup> For devices procured with a total ionizing dose tolerance guarantee, the post-irradiation performance is guaranteed at 25×C per MIL-STD-883 Method 1019, Condition A up to the maximum TID level procured.

### **Packaging**



#### **UT54ACTS04E: SMD**



#### Notes:

- 1. Lead finish (A,C, or X) must be specified.
- 2. If an "X" is specified when ordering, part marking will match the lead finish and will be either "A" (solder) or "C" (gold).
- 3. Total dose radiation must be specified when ordering. QML Q and QML V not available without radiation hardening. For prototype inquiries, contact factory.
- 4. Device type 02 is only offered with a TID tolerance guarantee of 3E5 rads(Si) or 1E6 rads(Si) and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A and section 3.11.2. Device type 03 is only offered with a TID tolerance guarantee of 1E5 rads(Si), 3E5 rads(Si), and 5E5 rads(Si), and is tested in accordance with MIL-STD-883 Test Method 1019 Condition A.

### Aeroflex Colorado Springs - Datasheet Definition

Advanced Datasheet - Product In Development

Preliminary Datasheet - Shipping Prototype

Datasheet - Shipping QML & Reduced Hi-Rel

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